TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

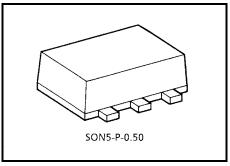
TC7SH126FE

Bus Buffer

Features

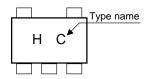
High speed: $t_{pd}=3.8$ ns (typ.) at $V_{\rm CC}=5$ V Low power dissipation: $I_{\rm CC}=2~\mu A$ (max) at Ta = 25°C High noise immunity: $V_{\rm NIH}=V_{\rm NIL}=28\%$ V $_{\rm CC}$ (min) 5.5V tolerant input.

Wide operating voltage range: $V_{\rm CC}$ (opr) = 2~5.5 V

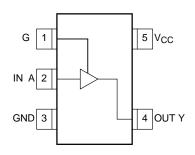


Weight: 0.003 g (typ.)

Marking



Pin Assignment (top view)



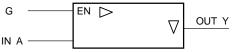
Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Supply voltage range	Vcc	-0.5~7	V
DC input voltage	V _{IN}	-0.5~7	V
DC output voltage	Vout	-0.5~V _{CC} + 0.5	V
Input diode current	lıк	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	P _D	150	mW
Storage temperature	T _{stg}	-65~150	°C



Logic Diagram

EN IN



G	Α	Υ
L	Х	Z
Н	L	L
Н	Н	Н

Truth Table

Recommended Operating Conditions

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2~5.5	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	V _{OUT}	0~ V _{CC}	V	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~100 (V_{CC} = 3.3 V \pm 0.3 V)	ns/V	
input rise and rail time	αι/αν	0~20 (V_{CC} = 5 V ± 0.5 V)	113/ V	

Electrical Characteristics

DC Characteristics

Characteristics Symbol Test Circuit		Test	est Took Condition			Ta = 25°C			Ta = -40~85°C		Unit
		Test Condition		V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit	
High-level input voltage			_		2.0	1.5	_	_	1.5	_	V
		_			3.0~5.5	V _{CC} × 0.7	_	_	V _{CC} × 0.7	_	
Low lovel input					2.0	_	_	0.5	_	0.5	
Low-level input voltage	_	_		3.0~5.5	_	_	V _{CC} × 0.3	_	V _{CC} × 0.3	V	
			V _{IN} = V _{IH}	I _{OH} = -50 μA	2.0	1.9	2.0	_	1.9	_	V
	High-level output voltage	_			3.0	2.9	3.0	_	2.9	_	
					4.5	4.4	4.5	_	4.4	_	
				$I_{OH} = -4 \text{ mA}$	3.0	2.58	_	_	2.48	_	
				$I_{OH} = -8 \text{ mA}$	4.5	3.94		_	3.80		
				I _{OL} = 50 μA	2.0	_	0	0.1	_	0.1	_
					3.0		0	0.1	_	0.1	
Low-level output voltage	_	VIN = VIH		4.5		0	0.1	_	0.1	V	
			$I_{OL} = 4 \text{ mA}$	3.0		_	0.36	_	0.44		
				$I_{OL} = 8 \text{ mA}$	4.5		_	0.36	_	0.44	
Input leakage current	I _{IN}	_	V _{IN} = 5.5 V or GND		0~5.5	_	_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	_	V _{IN} = V _{CC} or GND		5.5		_	2.0		20.0	μА



AC Characteristics (input: $t_r = t_f = 3$ ns)

Characteristics S	Symbol	Test Circuit	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
	Symbol			V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	
	^t pLH ^t pHL	_	_	3.3 ± 0.3	15	_	5.6	8.0	1.0	9.5	ns ns
Propagation delay					50	_	8.1	11.5	1.0	13.0	
time				5.0 ± 0.5	15	1	3.8	5.5	1.0	6.5	
					50		5.3	7.5	1.0	8.5	
	^t pZL ^t pZH	_	_	3.3 ± 0.3	15		5.4	8.0	1.0	9.5	
3-state output enable time					50		7.9	11.5	1.0	13.0	
				5.0 ± 0.5	15		3.6	5.1	1.0	6.0	
					50		5.1	7.1	1.0	8.0	
3-state output disable time	t _{pLZ}	_		3.3 ± 0.3	50		9.5	13.2	1.0	15.0	ns
	t _{pHZ}			5.0 ± 0.5	50		6.1	8.8	1.0	10.0	115
Input capacitance	C _{IN}	_		_			4	10	_	10	pF
Output capacitance	C _{OUT}	_		_			6		_	_	pF
Power dissipation capacitance	C _{PD}	_			(Note)		14		_	_	pF

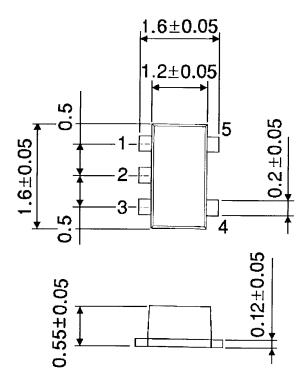
Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation.

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Package Dimensions

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

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